PSMN4R4-80PS

N-channel 80 V, 4.1 mΩ standard level FET

Rev. 01 — 18 June 2009 Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for standard level gate drive sources

1.3 Applications

- DC - DC converters
- Load switch
- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference

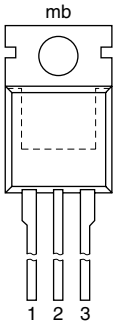
Symbol	Parameter	Conditions		Min	Typ	Max	Unit
I_D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see Figure 1; see Figure 3		-	-	100	A
P_{tot}	total power dissipation	T_{mb} = 25 °C; see Figure 2		-	-	306	W
Dynamic characteristics							
Q_{GD}	gate-drain charge	V_{GS} = 10 V; I_D = 80 A; V_{DS} = 40 V; see Figure 14; see Figure 15		-	25	-	nC
Static characteristics							
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 15 A; T_j = 25 °C; see Figure 6; see Figure 13	[1]	-	3.3	4.1	mΩ

[1] Measured 3 mm from package.

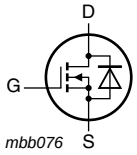
2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain		
3	S	source		
mb	D	drain		



SOT78
(TO-220AB; SC-46)



3. Ordering information

Table 3. Ordering information

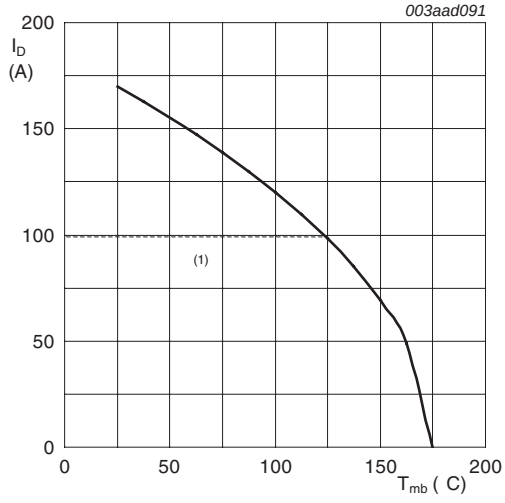
Type number	Package		
	Name	Description	Version
PSMN4R4-80PS	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

4. Limiting values

Table 4. Limiting values

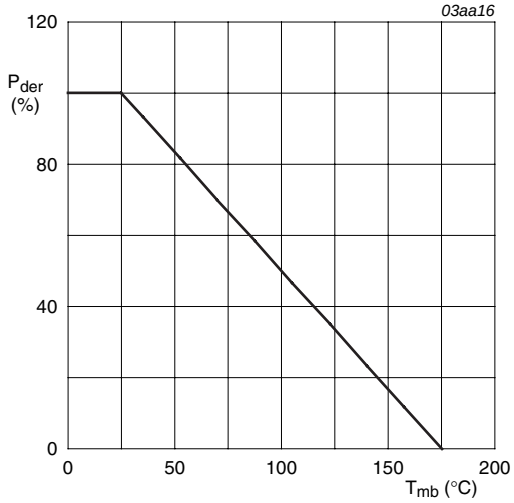
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25$ °C; $T_j \leq 175$ °C	-	80	V
V_{DGR}	drain-gate voltage	$T_j \geq 25$ °C; $T_j \leq 175$ °C; R_{GS} = 20 kΩ	-	80	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	V_{GS} = 10 V; T_{mb} = 100 °C; see Figure 1; see Figure 3	-	100	A
		V_{GS} = 10 V; T_{mb} = 25 °C; see Figure 1; see Figure 3	-	100	A
I_{DM}	peak drain current	$t_p \leq 10$ µs; pulsed; T_{mb} = 25 °C; see Figure 3	-	680	A
P_{tot}	total power dissipation	T_{mb} = 25 °C; see Figure 2	-	306	W
T_{stg}	storage temperature		-55	175	°C
T_j	junction temperature		-55	175	°C
Source-drain diode					
I_S	source current	T_{mb} = 25 °C	-	100	A
I_{SM}	peak source current	$t_p \leq 10$ µs; pulsed; T_{mb} = 25 °C	-	680	A
Avalanche ruggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; $V_{sup} \leq 80$ V; R_{GS} = 50 Ω; unclamped	-	591	mJ



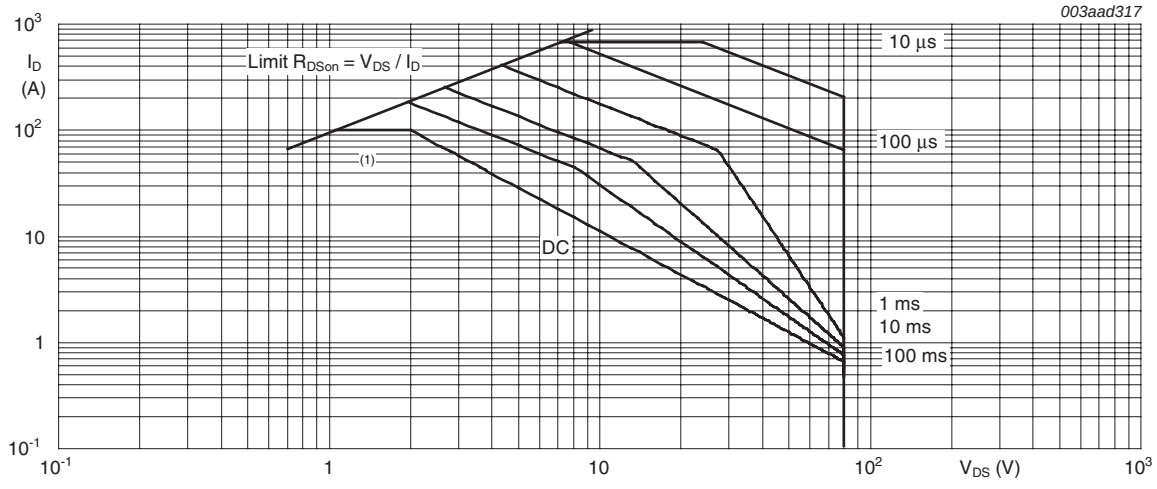
$$I_{der} = \frac{I_D}{I_{D(25°C)}} \times 100\,\%$$

Fig 1. Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25°C)}} \times 100\,\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



$T_j = 25\,°C$

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.23	0.49	K/W

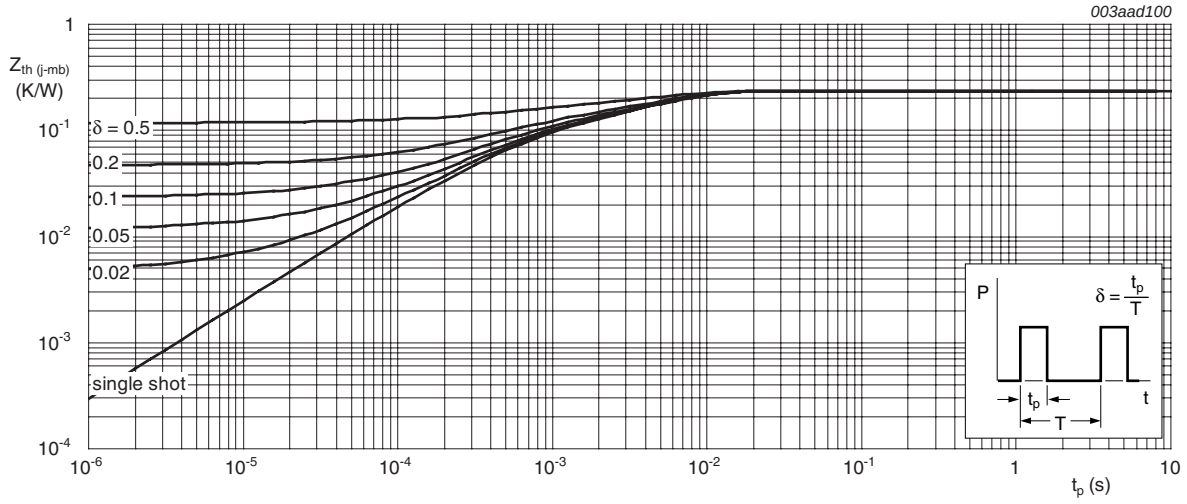


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

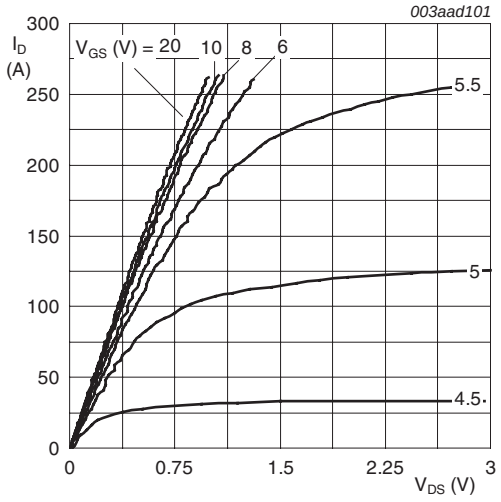
Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
$V_{(BR)DSS}$	drain-source breakdown voltage	I_D = 250 µA; V_{GS} = 0 V; T_j = -55 °C		73	-	-	V
		I_D = 250 µA; V_{GS} = 0 V; T_j = 25 °C		80	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS}; T_j = 175 °C; see Figure 11		1	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = -55 °C; see Figure 11		-	-	4.6	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = 25 °C; see Figure 11; see Figure 12		2	3	4	V
I_{DSS}	drain leakage current	V_{DS} = 80 V; V_{GS} = 0 V; T_j = 25 °C		-	-	10	µA
		V_{DS} = 80 V; V_{GS} = 0 V; T_j = 125 °C		-	-	200	µA
I_{GSS}	gate leakage current	V_{GS} = -20 V; V_{DS} = 0 V; T_j = 25 °C		-	-	100	nA
		V_{GS} = 20 V; V_{DS} = 0 V; T_j = 25 °C		-	-	100	nA
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 15 A; T_j = 175 °C; see Figure 13	[2]	-	7.6	9.47	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 100 °C; see Figure 13		-	5.5	6.8	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 25 °C; see Figure 6; see Figure 13	[2]	-	3.3	4.1	mΩ
R_G	internal gate resistance (AC)	f = 1 MHz		-	1	-	Ω
Dynamic characteristics							
$Q_{G(tot)}$	total gate charge	I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V		-	112	-	nC
		I_D = 80 A; V_{DS} = 40 V; V_{GS} = 10 V; see Figure 14; see Figure 15		-	125	-	nC
Q_{GS}	gate-source charge	I_D = 80 A; V_{DS} = 40 V; V_{GS} = 10 V; see Figure 14; see Figure 15		-	39	-	nC
$Q_{GS(th)}$	pre-threshold gate-source charge			-	24	-	nC
$Q_{GS(th-pl)}$	post-threshold gate-source charge			-	15	-	nC
Q_{GD}	gate-drain charge			-	25	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	I_D = 25 A; V_{DS} = 40 V; see Figure 14; see Figure 15		-	4.65	-	V
C_{iss}	input capacitance	V_{DS} = 40 V; V_{GS} = 0 V; f = 1 MHz; T_j = 25 °C; see Figure 16		-	8400	-	pF
C_{oss}	output capacitance			-	700	-	pF
C_{rss}	reverse transfer capacitance			-	336	-	pF
$t_{d(on)}$	turn-on delay time	V_{DS} = 40 V; R_L = 0.5 Ω; V_{GS} = 10 V; $R_{G(ext)}$ = 1.5 Ω		-	34.7	-	ns
t_r	rise time			-	38.1	-	ns
$t_{d(off)}$	turn-off delay time			-	66	-	ns
t_f	fall time			-	18.4	-	ns

Table 6. Characteristics *...continued*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Source-drain diode						
V_{SD}	source-drain voltage	I_S = 25 A; V_{GS} = 0 V; T_j = 25 °C; see Figure 17	-	0.8	1.2	V
t_{rr}	reverse recovery time	I_S = 25 A; dI_S/dt = 100 A/µs; V_{GS} = 0 V; V_{DS} = 20 V	-	59	-	ns
Q_r	recovered charge		-	130	-	nC

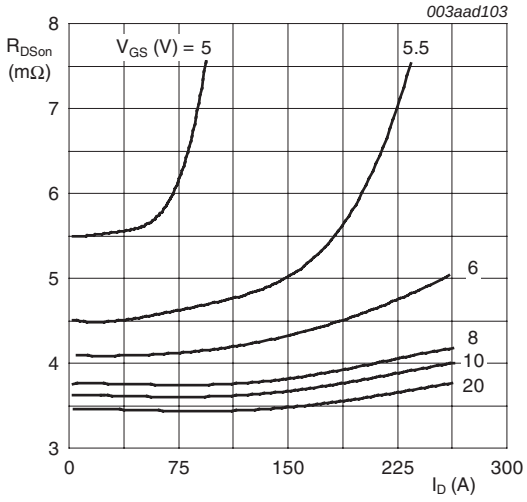
[1] Tested to JEDEC standards where applicable.

[2] Measured 3 mm from package.



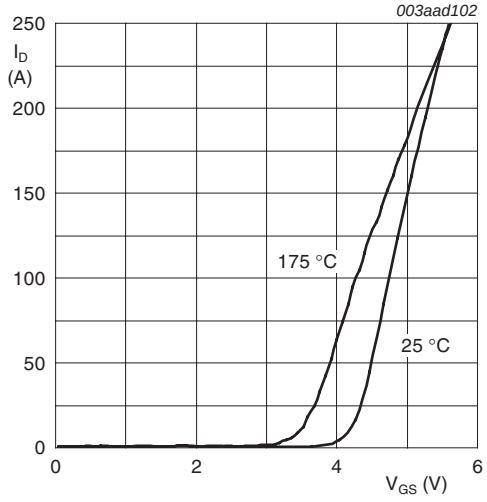
$T_j = 25\,°C$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



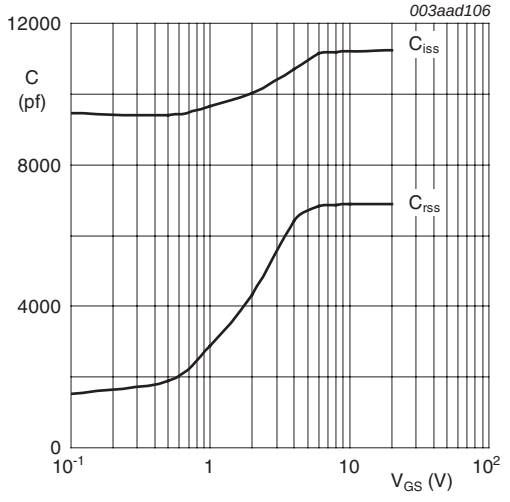
$T_j = 25\,°C; I_D = 15A$

Fig 6. Drain-source on-state resistance as a function of drain current; typical values



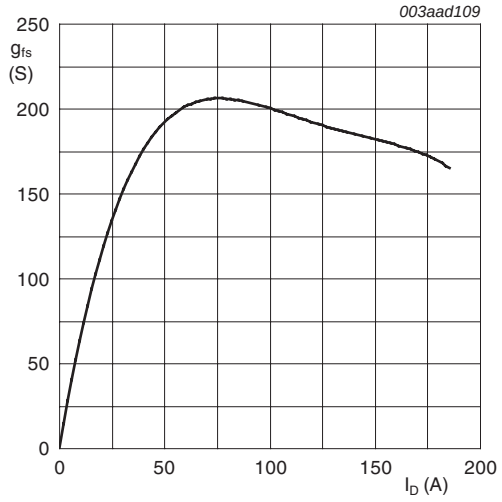
$V_{DS} > I_D \times R_{DSon}$

Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



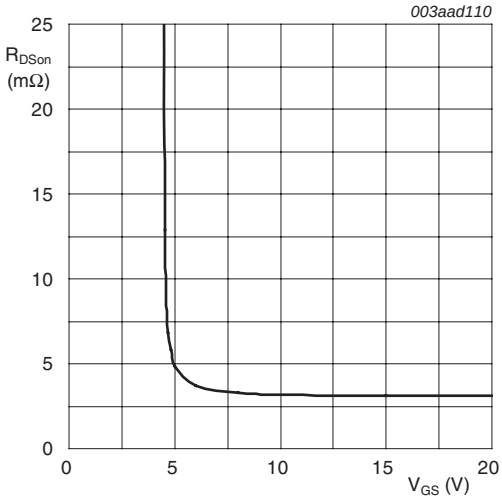
$V_{DS} = 0V; f = 1MHz$

Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



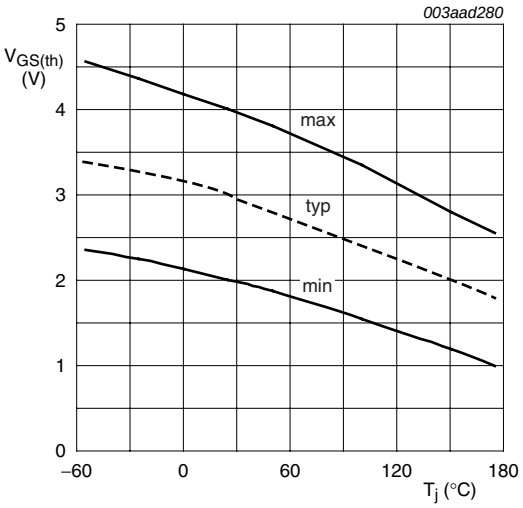
$T_j = 25\,°C; V_{DS} = 25\,V$

Fig 9. Forward transconductance as a function of drain current; typical values



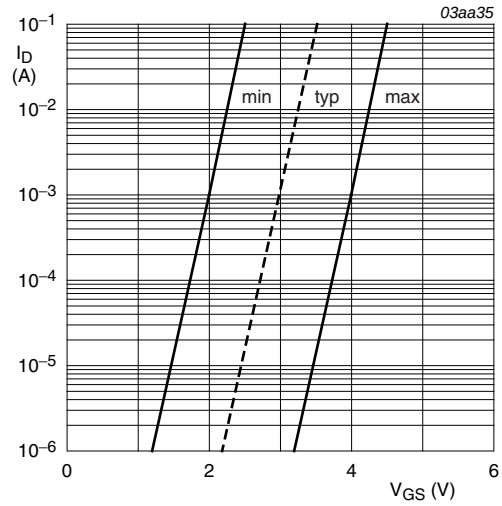
$T_j = 25\,°C; I_D = 15\,A$

Fig 10. Drain-source on-state resistance as a function of gate-source voltage; typical values



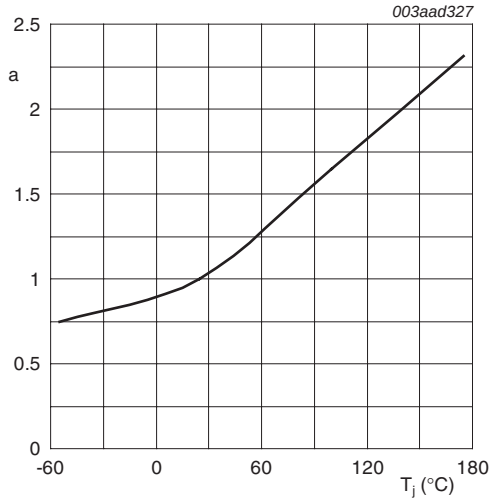
$I_D = 1\,mA; V_{DS} = V_{GS}$

Fig 11. Gate-source threshold voltage as a function of junction temperature



$T_j = 25\,°C; V_{DS} = 5\,V$

Fig 12. Sub-threshold drain current as a function of gate-source voltage



$$a = \frac{R_{DSon}}{R_{DSon(25°C)}}$$

Fig 13. Normailzed drain-source on-state resistance factor as a function of junction temperature

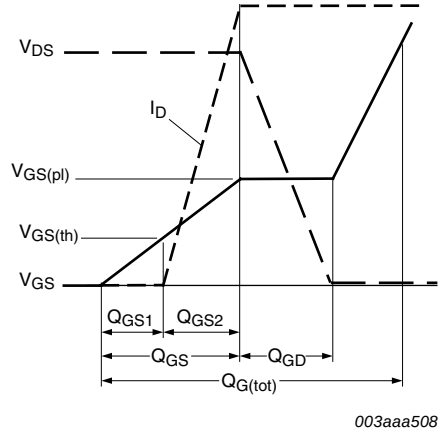
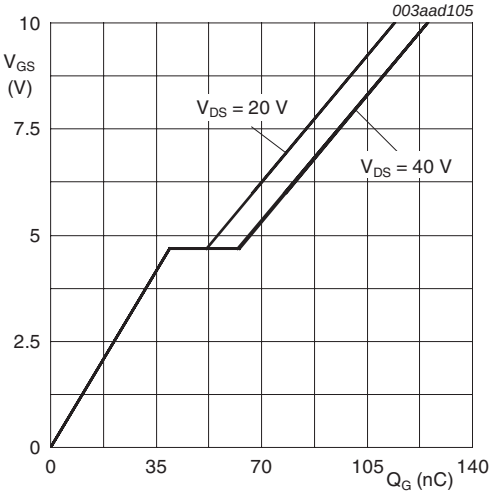
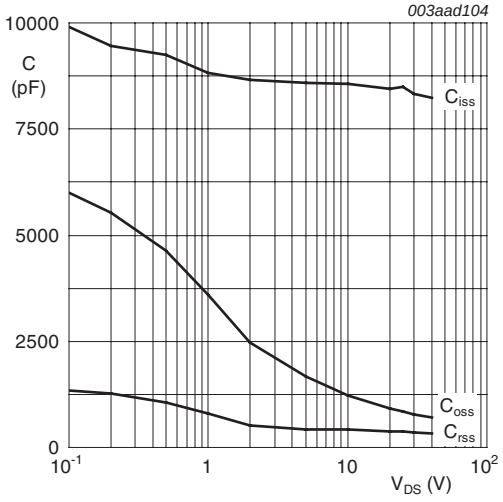


Fig 14. Gate charge waveform definitions



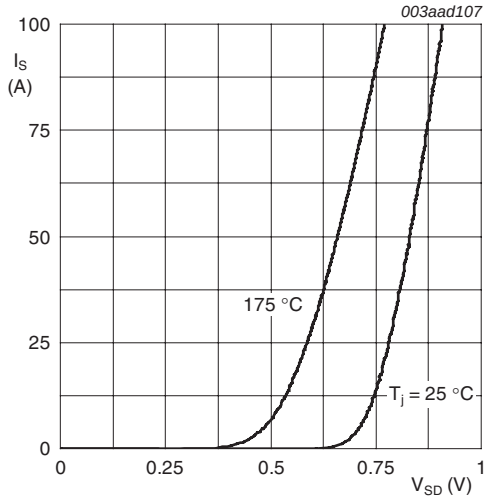
$$I_D = 80A$$

Fig 15. Gate-source voltage as a function of gate charge; typical values



$$V_{GS} = 0V; f = 1MHz$$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

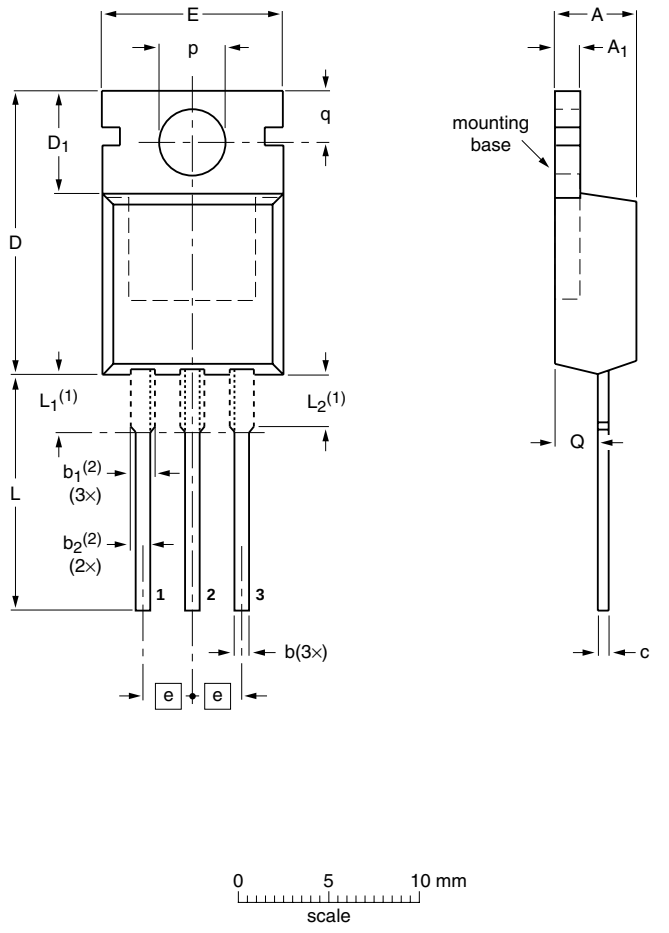


$V_{GS} = 0\,V$

Fig 17. Source current as a function of source-drain voltage; typical values

7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB **SOT78**



DIMENSIONS (mm are the original dimensions)

UNIT	A	A_1	b	b_1(2)	b_2(2)	c	D	D_1	E	e	L	L_1(1)	L_2(1) max.	p	q	Q
mm	4.7 4.1	1.40 1.25	0.9 0.6	1.6 1.0	1.3 1.0	0.7 0.4	16.0 15.2	6.6 5.9	10.3 9.7	2.54	15.0 12.8	3.30 2.79	3.0	3.8 3.5	3.0 2.7	2.6 2.2

Notes

1. Lead shoulder designs may vary.
2. Dimension includes excess dambar.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT78		3-lead TO-220AB	SC-46			~~08-04-23~~ 08-06-13

Fig 18. Package outline SOT78 (TO-220AB)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN4R4-80PS_1	20090618	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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11. Contents

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